

INTERFERENCE

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L15	1	((tim\$4 near5 analy\$4) same static) and parameter and delay and (slack same value) and (critical same path) and variation and digital and sensit\$6 and pair and test).CLM.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/10 08:50

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2194	((tim\$4 near5 analy\$4) same static	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/10 07:52
L2	364	((tim\$4 near5 analy\$4) same static) and parameter and (delay same path)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/10 07:52
L3	128	((tim\$4 near5 analy\$4) same static) and parameter and (delay same path) and slack	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/10 07:52
L4	88	((tim\$4 near5 analy\$4) same static) and parameter and (delay same path) and slack and (critical same path) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/10 07:52
L5	96	((tim\$4 near5 analy\$4) same static) and parameter and (delay same path) and slack and (critical same path)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/10 07:52
L6	45	((tim\$4 near5 analy\$4) same static) and parameter and (delay same path) and (slack same value) and (critical same path) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/10 07:52
L7	27	((tim\$4 near5 analy\$4) same static) and parameter and (delay same path) and (slack same value) and (critical same path) and "716"/\$.ccls. and digital	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/10 07:52
L8	16	((tim\$4 near5 analy\$4) same static) and parameter and (delay same path) and (slack same value) and (critical same path) and "716"/\$.ccls. and digital and sensit\$6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/10 08:20

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L9	18	((tim\$4 near5 analy\$4) same static) and parameter and (delay same path) and (slack same value) and (critical same path) and variation and digital and sensit\$6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/10 08:48
L10	5	((tim\$4 near5 analy\$4) same static) and parameter and (delay same path) and (slack same value) and (critical same path) and variation and digital and sensit\$6 and distinct	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/10 08:42
L11	1	((tim\$4 near5 analy\$4) same static) and parameter and (delay same path) and (slack same value) and (critical same path) and variation and digital and sensit\$6 and distinct and pair	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/10 08:44
L13	1	((tim\$4 near5 analy\$4) same static) and parameter and (delay same path) and (slack same value) and (critical same path) and variation and digital and sensit\$6 and distinct and pair and test	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/10 08:47
L15	1	((tim\$4 near5 analy\$4) same static) and parameter and delay and (slack same value) and (critical same path) and variation and digital and sensit\$6 and pair and test).CLM.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/10 08:50

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IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

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- ☐ 1. Gate sizing using incremental parameterized statistical timing analysis
Guthaus, M.R.; Venkateswarant, N.; Visweswariaht, C.; Zolotov, V.;
[Computer-Aided Design, 2005. ICCAD-2005. IEEE/ACM International Conference](#)
6-10 Nov. 2005 Page(s):1029 - 1036
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